

**Search Notes**

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Annan Q. Shang

Applicant(s)/Patent under  
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TANIGAWA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
725	37-61	2/8/2006	A.S

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR